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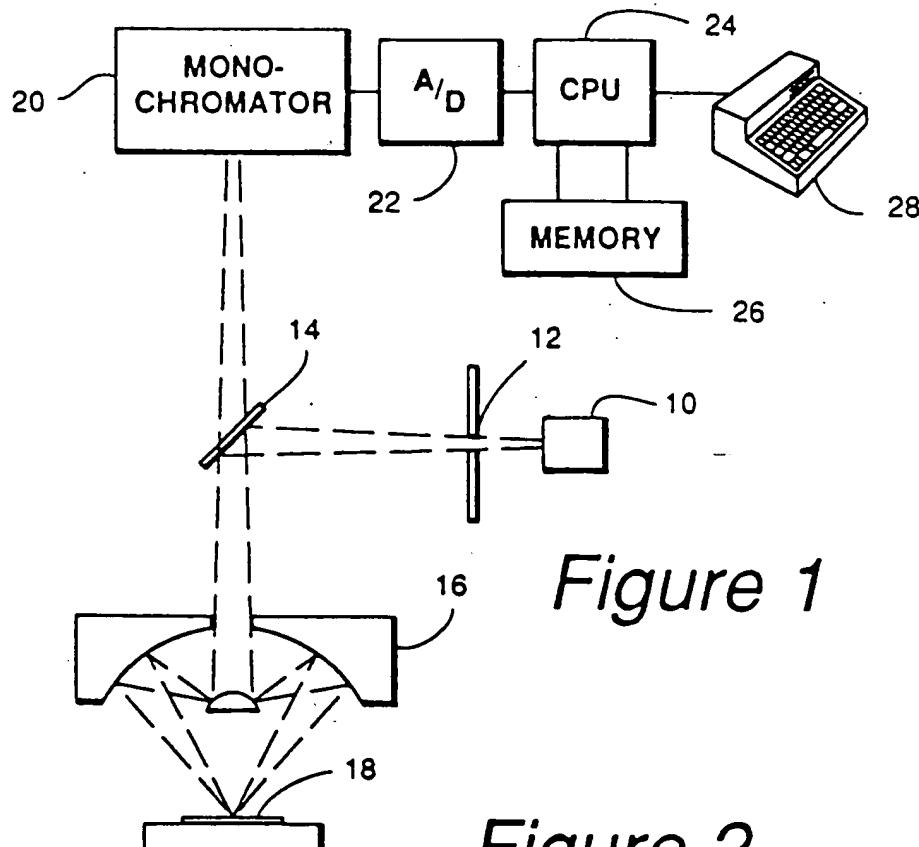


Figure 2

AT WAVELENGTH  $\lambda$ , MEASURE REFLECTANCE,  $m_R$ ,  
OF SAMPLE WITH KNOWN ABSOLUTE RELECTANCE,  $a_R$ .  
STORE VALUES OF  $\lambda$ ,  $m_R$  AND  $a_R$

DIVIDE  $m_R$  BY  $a_R$  TO OBTAIN SYSTEM EFFICIENCY  
COEFFICIENT,  $Z\lambda$ , AT WAVELENGTH  $\lambda$

STORE  $Z\lambda$  IN MEMORY

WITH SAME OPTICAL SYSTEM AND SAME WAVELENGTH  
MEASURE REFLECTANCE,  $m_{Rx}$ , OF SAMPLE,  $x$

DIVIDE [MULTIPLY]  $m_{Rx}$  BY  $Z\lambda$  TO OBTAIN ABSOLUTE  
REFLECTANCE,  $a_{Rx}$ , OF SAMPLE  $x$